

Application number 10/775,716  
Amendment dated August 4, 2005  
Reply to office action mailed April 5, 2005

PATENT

**Amendments to the Abstract:**

Please replace the abstract with the following:

Circuits, methods, and apparatus for output response analyzers that may be used during integrated circuit testing. Current output test data is compared with previous output test data. In this way, repetitive test patterns such as checkerboards may be employed while limiting circuit complexity. The outputs of several built-in self-test circuits may be combined into as few as one signal that may be provided as a test output.